

Particle Characterization: Module 12, Lecture 36

1. Define yield.
2. Define reliability.
3. Give an example where yield & reliability are inversely correlated.
4. How is yield related to defect density?
5. Plot probability of failure versus particle size with & without chemical effects.
6. Draw typical Pareto chart of defects in a high-tech product.
7. How is minimum particle size that causes failures related to critical product dimensions?
8. How does particle adhesion affect yield & reliability differently?
9. What implications does the Semiconductor Technology Roadmap have for particle controls?
10. Why is it better to not have a uniform distribution of defects in product manufacturing?